

byko-test 4200/4500

Dry Film Thickness Gages

The byko-test 4500/4200 film thickness gauges allows for the measurement of a variety of products. No cable exchange or calibration is needed when changing from a ferrous to a non-ferrous substrate. The large LCD display and 10 second retention of the last measured value makes the byko-test 4500/4200 easy to use.

- Compact pocket size instrument
- One-handed design for ease of use
- Switchable from mils to microns
- Strong, wear resistant ruby probe tip
- V-groove in probe for positioning on cylindrical parts
- Acoustic signal for measurement confirmation
- Automatic substrate recognition
- Extended measuring range
- Faster measuring speed
- Graphic display with backlight

For sample areas that are difficult to reach, the byko-test 4500/4200 EC models come with an 1 meter length extension cable. The extension cable offers more flexibility to position the sensor.

Standards

ASTM	B 499, D 1186, D 1400, D 7091
BS	3900 Part C5, 5411 (3,11)
DIN	50981, 50984
ISO	2360, 2808, 2178



byko-test with extension cable

Ordering Information

Cat. No.	Description
3634	byko-test 4200 Fe
3636	byko-test 4200 Fe EC, probe 3638
3635	byko-test 4500 Fe/NFe
3637	byko-test 4500 Fe/NFe EC, probe 3639

Cat. No. PG-3635 Comes complete with:

byko-test gage
Carrying case with zero plates
Operating instructions
Calibration Certificate
2 AA batteries
Extension cable (1meter) for 3636, 3637 only

Technical Specifications

Substrate Fe	steel or iron
Substrate NFe	non-magnetic metals: aluminum, copper, brass, zinc, stainless steel
Measuring Range	Fe: 0 - 3000 μ m (0 - 120 mils) NFe: 0 - 3000 μ m (0 - 120 mils)
Accuracy	$\pm (2\mu\text{m} + 3\%^*)$
Minimum Curvature	5 mm (0.2 in) convex; 30 mm (1.2 in) concave
Minimum Substrate Thickness	Fe: 0.2 mm (0.01 in) NFe 0,05 mm (0,002 in)
Minimum Area of Measurement	10 x 10 mm (0.4 x 0.4 in)
Operating Temperature	0 - 60 °C (32 - 140 °F)
Power Supply	2 x AA Batteries
Dimensions	100 x 62 x 27 mm (4 x 2.5 x 1.1 in)
Weight	approx. 130 g (4.6 oz) with battery

*Note: of measured value